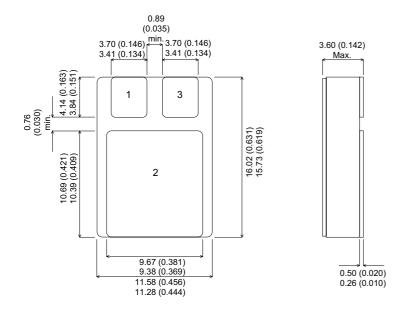


## IRF9130SMD05 **IRFN9130SMD05**

#### **MECHANICAL DATA**

Dimensions in mm (inches)



#### SMD<sub>5</sub>

### IRF9130SMD05

PAD1 = GATE PAD 2 DRAIN PAD3 = SOURCE

#### **IRFN9130SMD05**

PAD1 = SOURCE PAD 2 = DRAIN PAD3 = GATE

# P-CHANNEL **POWER MOSFET** FOR HI-REL **APPLICATIONS**

V<sub>DSS</sub> -100V I<sub>D(cont)</sub> -8A R<sub>DS(on)</sub>  $0.35\Omega$ 

### **FEATURES**

- HERMETICALLY SEALED
- SIMPLE DRIVE REQUIREMENTS
- LIGHTWEIGHT
- SCREENING OPTIONS AVAILABLE
- ALL LEADS ISOLATED FROM CASE

## **ABSOLUTE MAXIMUM RATINGS** (T<sub>case</sub> = 25°C unless otherwise stated)

$V_{GS}$	Gate – Source Voltage	±20V
$I_{D}$	Continuous Drain Current @ T <sub>case</sub> = 25°C	8A
I <sub>D</sub>	Continuous Drain Current @ T <sub>case</sub> = 100°C	5A
$I_{DM}$	Pulsed Drain Current	40A
$P_{D}$	Power Dissipation @ T <sub>case</sub> = 25°C	45W
	Linear Derating Factor	0.36W/°C
$T_J$ , $T_stg$	Operating and Storage Temperature Range	−55 to 150°C
$R_{\theta JC}$	Thermal Resistance Junction to Case	2.8°C/W max.

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Prelim. 10/00



# IRF9130SMD05 **IRFN9130SMD05**

# **ELECTRICAL CHARACTERISTICS** ( $T_C = 25$ °C unless otherwise stated)

Parameter		Test Conditions		Min.	Тур.	Max.	Unit		
	STATIC ELECTRICAL RATINGS	•	•		•				
BV <sub>DSS</sub>	Drain – Source Breakdown Voltage	$V_{GS} = 0$	$I_D = 1mA$	100			V		
$\Delta BV_{DSS}$	Temperature Coefficient of	Reference to 25°C			0.4		\/\(\alpha\)		
$\Delta T_{J}$	Breakdown Voltage	I <sub>D</sub> = 1mA			0.1		V/°C		
R <sub>DS(on)</sub>	Static Drain – Source On–State	V <sub>GS</sub> = 10V	I <sub>D</sub> = 5A			0.35			
	Resistance	V <sub>GS</sub> = 10V	I <sub>D</sub> = 8A			0.4	$ \Omega$		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I <sub>D</sub> = 250μA	2		4	V		
9 <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> ≥ 15V	I <sub>DS</sub> = 5A	3			S(\Omega)		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{GS} = 0$	$V_{DS} = 0.8BV_{DSS}$			25	μΑ		
			T <sub>J</sub> = 125°C			250			
I <sub>GSS</sub>	Forward Gate – Source Leakage	V <sub>GS</sub> = 20V				100	^		
I <sub>GSS</sub>	Reverse Gate – Source Leakage	$V_{GS} = -20V$				-100	⊢ nA		
	DYNAMIC CHARACTERISTICS		Į.						
C <sub>iss</sub>	Input Capacitance	$V_{GS} = 0$			860				
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V			350		pF		
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1MHz		125					
Qg	Total Gate Charge	V <sub>GS</sub> = 10V	I <sub>D</sub> = 8A	40.5		00	nC		
		$V_{DS} = 0.5BV_{DS}$	SS	12.5		29			
Q <sub>gs</sub>	Gate - Source Charge	I <sub>D</sub> = 8A	1.0		6.3	nC			
$Q_{gd}$	Gate - Drain ("Miller") Charge	$V_{DS} = 0.5BV_{DS}$	2		27				
t <sub>d(on)</sub>	Turn-On Delay Time	V 50V			60	- ns			
t <sub>r</sub>	Rise Time	$V_{DD} = 50V$			140				
t <sub>d(off)</sub>	Turn-Off Delay Time	$I_D = 8A$ $R_G = 7.5\Omega$					140		
t <sub>f</sub>	Fall Time						140		
	SOURCE - DRAIN DIODE CHARAC	TERISTICS							
I <sub>S</sub>	Continuous Source Current					8	A		
I <sub>SM</sub>	Pulse Source Current					32			
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> = 8A	$T_J = 25^{\circ}C$			4.7	V		
		$V_{GS} = 0$				4.7			
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> = 8A	$T_J = 25^{\circ}C$			300	ns		
Q <sub>rr</sub>	Reverse Recovery Charge	$d_i / d_t \le 100A/\mu$	s V <sub>DD</sub> ≤50V			3	μС		
	PACKAGE CHARACTERISTICS		L				1		
L <sub>D</sub>	Internal Drain Inductance (from 6mm down drain lead pad to centre of die)				8.7		لام		
L <sub>S</sub>	Internal Source Inductance (from 6mm down source lead to centre of source bond pad)				8.7		– nH		